

**AMENDMENTS TO THE SPECIFICATION**

Please REPLACE the current title with:

-- MINERAL ANALYSIS ---

Please INSERT the following subheading and paragraph after the Title of the Invention to read as follows:

-- CROSS REFERENCE TO RELATED APPLICATIONS

This National Stage application is a continuation-in-part of co-pending International Patent Application No. PCT/ZA03/00011, filed January 22, 2003 by Francois Eberhardt DU PLESSIS entitled SPECTRAL ANALYSIS APPARATUS FOR MEASURING INTERMEDIATE LAYERS OF MINERAL SAMPLERS, the entire contents of which is incorporated by reference, and for which priority is claimed under U.S.C. § 371. As in the parent International Application No. PCT/ZA03/00011, priority is also claimed to co-pending South African Patent Application Nos. 2002/0578 (filed January 23, 2002), 2002/0579 (filed January 23, 2002), and 2002/5000 (filed June 21, 2002), the entire contents of which are incorporated by reference for which priority is claimed under 35 U.S.C. § 119. --